# High Speed, High Gain Bipolar NPN Transistor with Antisaturation Network and Transient Voltage Suppression Capability

The BUD42D is a state-of-the-art bipolar transistor. Tight dynamic characteristics and lot to lot minimum spread make it ideally suitable for light ballast applications.

#### **Features**

- Free-Wheeling Diode Built-In
- Flat DC Current Gain
- Fast Switching Times and Tight Distribution
- "6 Sigma" Process Providing Tight and Reproducible Parameter Spreads
- Epoxy Meets UL 94 V-0 @ 0.125 in
- ESD Ratings: Machine Model, C; >400 V Human Body Model, 3B; >8000 V
- Pb-Free Packages are Available

#### **Two Versions**

- BUD42D-1: Case 369D for Insertion Mode
- BUD42D, BUD42DT4: Case 369C for Surface Mount Mode

#### **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
Collector–Emitter Sustaining Voltage	$V_{CEO}$	350	Vdc
Collector-Base Breakdown Voltage	$V_{CBO}$	650	Vdc
Collector–Emitter Breakdown Voltage	V <sub>CES</sub>	650	Vdc
Emitter-Base Voltage	V <sub>EBO</sub>	9	Vdc
Collector Current – Continuous – Peak (Note 1)	I <sub>C</sub> I <sub>CM</sub>	4.0 8.0	Adc
Base Current – Continuous – Peak (Note 1)	I <sub>B</sub> I <sub>BM</sub>	1.0 2.0	Adc
Total Device Dissipation @ T <sub>C</sub> = 25°C Derate above 25°C	P <sub>D</sub>	25 0.2	W W/°C
Operating and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	-65 to +150	°C

#### **TYPICAL GAIN**

Typical Gain @ I <sub>C</sub> = 1 A, V <sub>CF</sub> = 2 V	hee	13	_
Typical Gain @ $I_C = 0.3 \text{ A}$ , $V_{CE} = 1 \text{ V}$	h <sub>FE</sub>	16	_

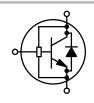
Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.



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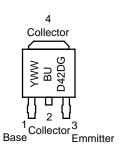
http://onsemi.com

# 4 AMPERES 650 VOLTS, 25 WATTS POWER TRANSISTOR

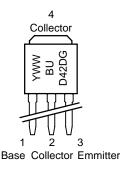


#### MARKING DIAGRAMS









Y = Year
WW = Work Week
BUD43D = Device Code
G = Pb-Free Package

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 10 of this data sheet.

1. Pulse Test: Pulse Width = 5.0 ms, Duty Cycle = 10%10

#### THERMAL CHARACTERISTICS

Characteristic		Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	5.0	°C/W
Thermal Resistance, Junction-to-Ambient		71.4	°C/W
Maximum Lead Temperature for Soldering Purposes: 1/8 in from Case for 5 seconds		260	°C

#### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

	Characteristic				Min	Тур	Max	Unit
OFF CHARACTERISTICS				•		•	•	•
Collector–Emitter Sustaining Voltage (I <sub>C</sub> = 100 mA, L = 25 mH)				V <sub>CEO(sus)</sub>	350	430	_	Vdc
Collector-Base Breakdown (I <sub>CBO</sub> = 1 mA)	Voltage			V <sub>CBO</sub>	650	780	_	Vdc
Emitter-Base Breakdown V (I <sub>EBO</sub> = 1 mA)	oltage			V <sub>EBO</sub>	9.0	12	_	Vdc
Collector Cutoff Current $(V_{CE} = Rated V_{CEO}, I_B = I_{CEO})$	0)		@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	I <sub>CEO</sub>	-	- -	100 200	μAdc
Collector Cutoff Current (V <sub>CE</sub> = Rated V <sub>CES</sub> , V <sub>EB</sub> = 0	0)		@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	I <sub>CES</sub>	- -	- -	10 200	μAdc
Emitter–Cutoff Current (V <sub>EB</sub> = 9 Vdc, I <sub>C</sub> = 0)				I <sub>EBO</sub>	-	_	100	μAdc
ON CHARACTERISTICS								
Base–Emitter Saturation Vo (I <sub>C</sub> = 1 Adc, I <sub>B</sub> = 0.2 Adc)	•			V <sub>BE(sat)</sub>	-	0.85	1.2	Vdc
Collector–Emitter Saturation Voltage (I <sub>C</sub> = 2 Adc, I <sub>B</sub> = 0.5 Adc)				V <sub>CE(sat)</sub>	1	0.2	1.0	Vdc
DC Current Gain $(I_C = 1 \text{ Adc, } V_{CE} = 2 \text{ Vdc})$ $(I_C = 2 \text{ Adc, } V_{CE} = 5 \text{ Vdc})$				h <sub>FE</sub>	8.0 10	13 12	_ _	-
DIODE CHARACTERISTICS								
Forward Diode Voltage (I <sub>EC</sub> = 1.0 Adc)				V <sub>EC</sub>	_	0.9	1.5	V
SWITCHING CHARACTERIS	STICS: Resistive Load	d (D.C.≤ 10%	6, Pulse Width = 40	μs)				
Turn–Off Time ( $I_C = 1.2 \text{ Adc}, I_{B1} = 0.4 \text{ A}, I_{B2} = 0.1 \text{ A}, V_{CC} = 300 \text{ V}$ )			T <sub>off</sub>	4.6	_	6.55	μS	
Fall Time $(I_C = 2.5 \text{ Adc}, I_{B1} = I_{B2} = 0.5 \text{ A}, V_{CC} = 150 \text{ V}, V_{BE} = -2 \text{ V})$			T <sub>f</sub>	_	_	0.8	μS	
DYNAMIC SATURATION VO	LTAGE							-
	I <sub>C</sub> = 400 mA	@ 1 μs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	V <sub>CE(dsat)</sub>	- -	2.8 3.2	_ _	V
Dynamic Saturation Voltage: Determined 1 μs and	$I_{B1} = 40 \text{ mA}$ $V_{CC} = 300 \text{ V}$	@ 3 μs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C		<u>-</u>	0.75 1.3	- -	
3 µs respectively after rising I <sub>B1</sub> reaches 90% of final I <sub>B1</sub>	I <sub>C</sub> = 1 A	@ 1 μs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	1	<u>-</u>	2.1 4.7	- -	
	$I_{B1} = 200 \text{ mA}$ $V_{CC} = 300 \text{ V}$	@ 3 μs	@ T <sub>C</sub> = 25°C @ T <sub>C</sub> = 125°C	1	- -	0.35 0.6	_ _	

#### TYPICAL STATIC CHARACTERISTICS

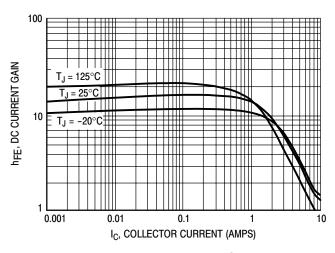


Figure 1. DC Current Gain @ V<sub>CE</sub> = 1 V

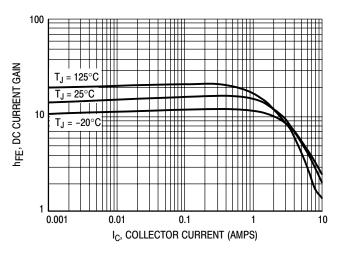


Figure 2. DC Current Gain @ V<sub>CE</sub> = 5 V

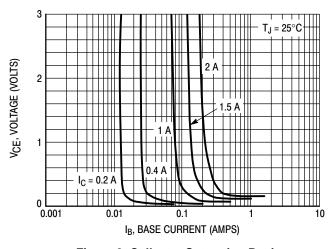


Figure 3. Collector Saturation Region

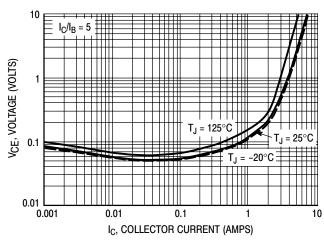


Figure 4. Collector-Emitter Saturation Voltage

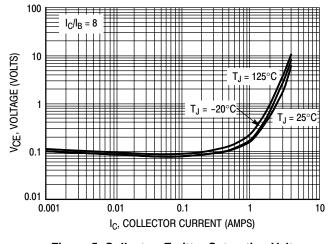


Figure 5. Collector-Emitter Saturation Voltage

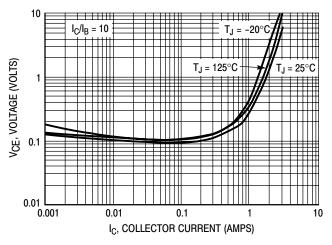


Figure 6. Collector-Emitter Saturation Voltage

#### TYPICAL STATIC CHARACTERISTICS

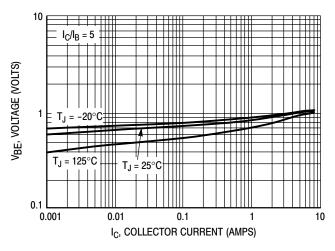


Figure 7. Base-Emitter Saturation Region

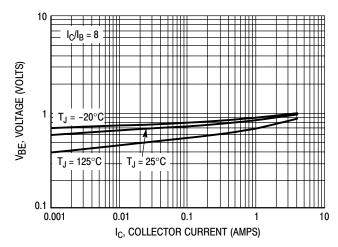


Figure 8. Base-Emitter Saturation Region

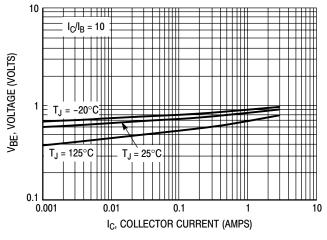


Figure 9. Base-Emitter Saturation Region

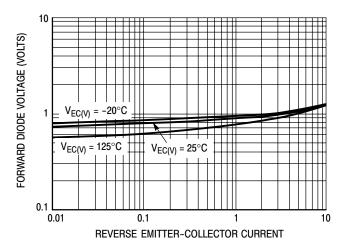


Figure 10. Forward Diode Voltage

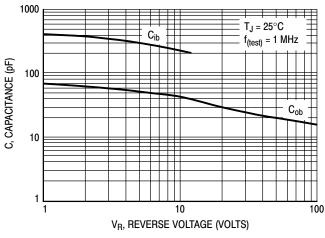


Figure 11. Capacitance

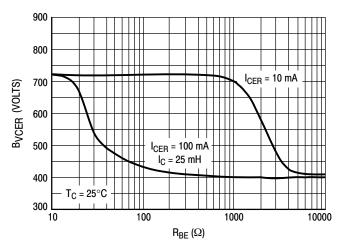


Figure 12.  $B_{VCER} = f(R_{BE})$ 

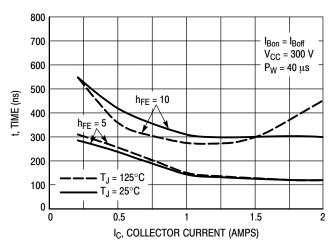


Figure 13. Resistive Switching, ton

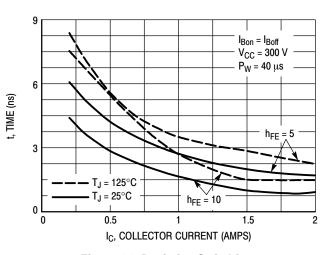


Figure 14. Resistive Switching, toff

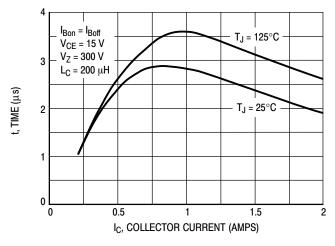


Figure 15. Inductive Storage Time,  $t_{si}$  @  $h_{FE} = 5$ 

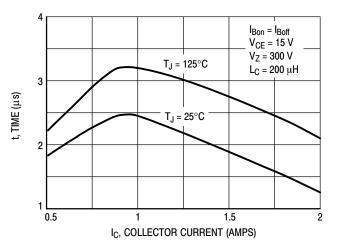


Figure 16. Inductive Storage Time,  $t_{si} @ h_{FE} = 10$ 

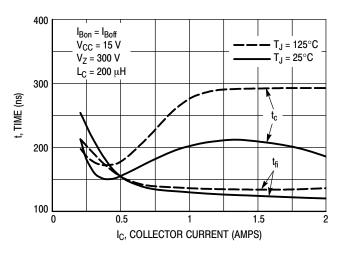


Figure 17. Inductive Fall and Cross Over Time,  $t_{fi}$  and  $t_{c}$  @  $h_{FE}$  = 5

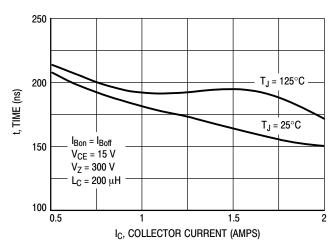


Figure 18. Inductive Fall Time,  $t_{fi}$  @  $h_{FE} = 10$ 

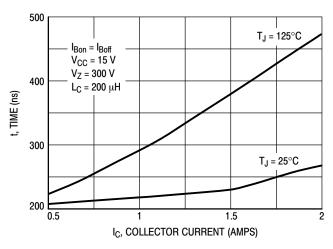


Figure 19. Inductive Cross Over Time,  $t_{\text{C}} \ @ \ h_{\text{FE}} = 10$ 

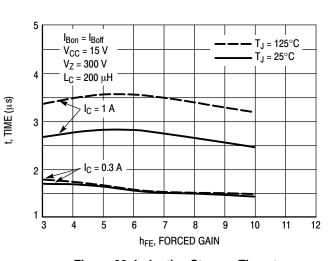


Figure 20. Inductive Storage Time,  $t_{\rm Si}$ 

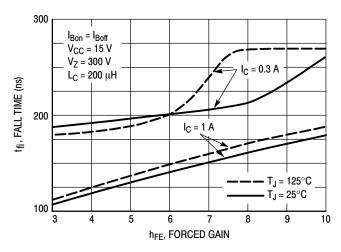


Figure 21. Inductive Fall Time, tf

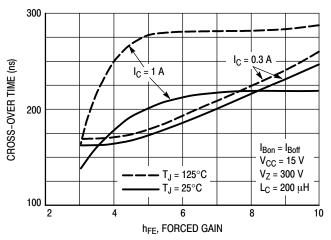


Figure 22. Inductive Cross Over Time, tc

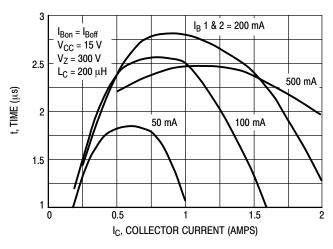


Figure 23. Inductive Storage Time, t<sub>si</sub>

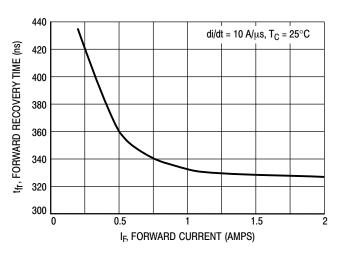


Figure 24. Forward Recovery Time, tfr

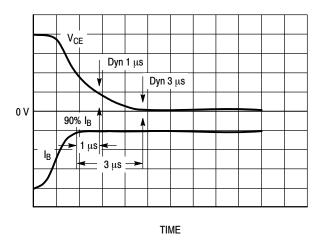


Figure 25. Dynamic Saturation Voltage Measurements

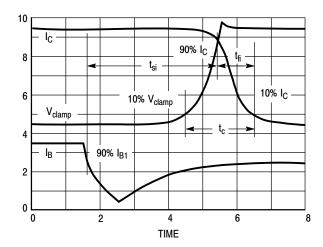
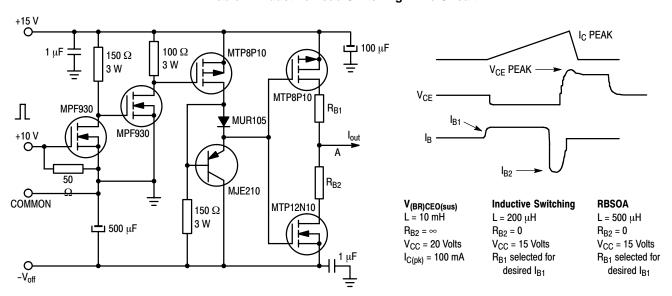


Figure 26. Inductive Switching Measurements

**Table 1. Inductive Load Switching Drive Circuit** 



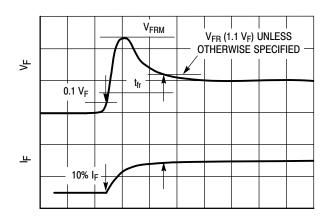


Figure 27. t<sub>fr</sub> Measurement

#### **MAXIMUM RATINGS**

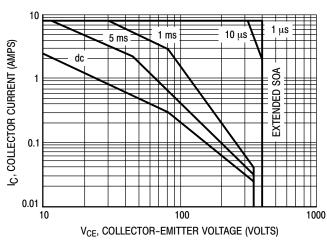


Figure 28. Forward Bias Safe Operating Area

Figure 29. Reverse Bias Safe Operating Area

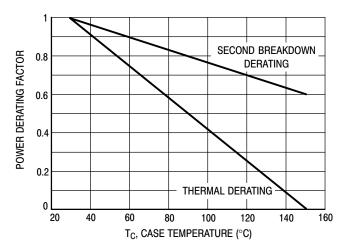


Figure 30. Power Derating

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate  $I_C$ – $V_{CE}$  limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate. The data of Figure 28 is based on  $T_C$  = 25°C;  $T_{j(pk)}$  is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to 10% but must be derated when  $T_C$  > 25°C. Second Breakdown limitations do not derate like thermal limitations. Allowable current at the voltages shown on

Figure 28 may be found at any case temperature by using the appropriate curve on Figure 30.

 $T_{j(pk)}$  may be calculated from the data in Figure 31. At any case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown. For inductive loads, high voltage and current must be sustained simultaneously during turn—off with the base to emitter junction reverse biased. The safe level is specified as reverse biased safe operating area (Figure 29). This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode.

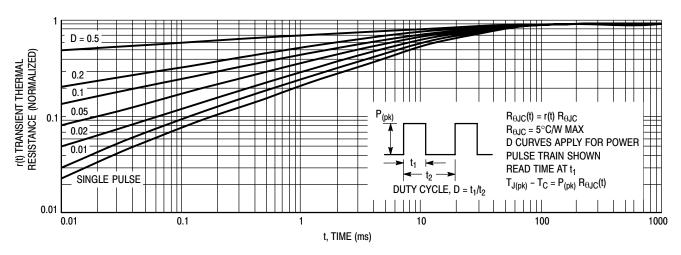


Figure 31. Thermal Response

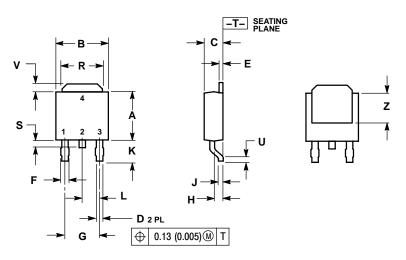
#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
BUD42D	DPAK	75 Units / Rail
BUD42DG	DPAK (Pb-Free)	75 Units / Rail
BUD42D-1	DPAK Straight Lead	75 Units / Rail
BUD42D-1G	DPAK Straight Lead (Pb-Free)	75 Units / Rail
BUD42DT4	DPAK	2500 Units / Tape & Reel
BUD42DT4G	DPAK (Pb-Free)	2500 Units / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### **PACKAGE DIMENSIONS**

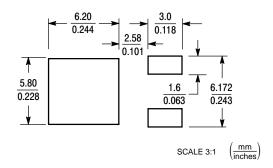
#### **DPAK** CASE 369C-01 ISSUE O



	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.22
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
Е	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.180	BSC	4.58 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.102	0.114	2.60	2.89
L	0.090	BSC	2.29 BSC	
R	0.180	0.215	4.57	5.45
S	0.025	0.040	0.63	1.01
U	0.020		0.51	
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

STYLE 1:
PIN 1. BASE
2. COLLECTOR
3. EMITTER
4. COLLECTOR

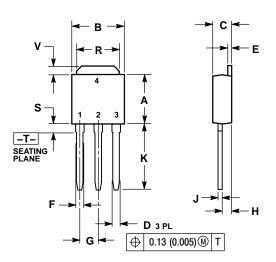
#### **SOLDERING FOOTPRINT\***

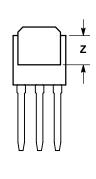


<sup>\*</sup>For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### PACKAGE DIMENSIONS

#### **DPAK** STRAIGHT LEAD CASE 369D-01 ISSUE B





- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982
  - CONTROLLING DIMENSION: INCH.

	INCHES		MILLIN	ETERS
DIM	MIN	MAX	MAX MIN	
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090 BSC		2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

STYLE 1: PIN 1. BASE

- 2. COLLECTOR 3. EMITTER
- 4. COLLECTOR

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